

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

the Application of

Ranjan RAY

Serial No.: 10/782,927

Filed: February 23, 2004

For: FINE GRAINED SPUTTERING TARGETS OF COBALT AND NICKEL BASE ALLOYS MADE VIA CASTING IN METAL MOLDS FOLLOWED BY HOT FORGING AND ANNEALING AND METHODS OF MAKING SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to Rules 56 and 98, Applicants hereby call the attention of the Patent Office to the references listed on the attached Form PTO 1449.

Applicants present these references so that the Patent Office may, in the first instance, determine any relevancy thereof to the presently claimed invention, see <u>Beckman Instruments</u>, <u>Inc. v. Chemtronics</u>, <u>Inc.</u>, 439 F.2d 1369, 1380, 165 USPQ 355, 364 (5th Cir. 1970). Also see Patent Office Rule 104. Applicants respectfully request that these references be expressly considered during the prosecution of this application and made of record herein and appear among the "References Cited" on any patent to issue herefrom.

Respectfully submitted,

Date:

APV/pgw

ATTORNEY DOCKET NO. APV31670

Bu:

Anthony P. Venturino

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FORM PTO-1449 U.S. Department of Commerce (Rev. 4/92)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

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APV31670	10/782,927
APPLICANT	
Ranjan RAY	
	

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FILING DATE February 23, 2004

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NA	IMB	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

US Published Patent Application No. 2004/0060685A1, (Ser. No. 10/674,435), RAY et al., filed October 1, 2003, published April 1, 2004
US Published Patent Application No. 2004/0055725A1, (Ser. No. 10/448,116), RAY et al., filed May 30, 2003, published March 25, 2004
US Published Patent Application No. 2004/0040690A1, (Ser. No. 10/443,807), RAY et al., filed May 23, 2003, published March 4, 2004
US Patent Application Serial No. 10/838,266, RAY et al., filed May 5, 2004

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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APPLICANT Ranjan RAY

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